Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/677,605	DEY ET AL.	
Examiner	**Art Unit**	
Erin M. File	2611	

SEARCHED			
Class	Subclass	Date	Examiner
375	260	5/10/2007	EMF

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST US PAT, USPGPUB, EPO, JPO DERWENT, IBM (text search only—see search history printout)	5/10/2007	EMF
PALM INVENTORSHIP	5/10/2007	EMF
PLUS Search	5/10/2007	EMF